

CoolMOS[™] **Power Transistor**

Features

- Lowest figure-of-merit $R_{ON} x Q_g$
- Ultra low gate charge
- Extreme dv/dt rated
- · High peak current capability
- Qualified according to JEDEC¹⁾ for target applications
- Pb-free lead plating; RoHS compliant

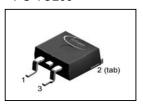
CoolMOS CP is designed for:

· Hard switching SMPS topologies

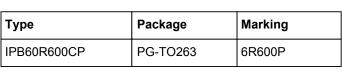
Product Summary

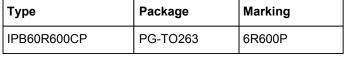
V _{DS} @ T _{j,max}	650	V
$R_{DS(on),max} @ T_j = 25^{\circ}C$	0.6	Ω
Q _{g,typ}	21	nC

PG-TO263



drain pin 2





Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C	6.1	А
		T _C =100 °C	3.8	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	15	
Avalanche energy, single pulse	E _{AS}	I _D =2.2 A, V _{DD} =50 V	144	mJ
Avalanche energy, repetitive $t_{AR}^{(2),3)}$	E _{AR}	I _D =2.2 A, V _{DD} =50 V	0.2	
Avalanche current, repetitive $t_{AR}^{(2),3)}$	I _{AR}		2.2	А
MOSFET dv/dt ruggedness	dv/dt	V _{DS} =0480 V	50	V/ns
Gate source voltage	V_{GS}	static	±20	V
		AC (f>1 Hz)	±30	
Power dissipation	P _{tot}	T _C =25 °C	60	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55 150	°C



Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current	Is	Т _С =25 °С	3.3	Α
Diode pulse current ²⁾	I _{S,pulse}	7 _C -23 G	15	
Reverse diode dv/dt ⁴⁾	dv/dt		15	V/ns

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R _{thJC}		-	-	2.1	K/W
	R _{thJA}	leaded	-	-	62	
Thermal resistance, junction - ambient	R _{thJA}	SMD version, device on PCB, minimal footprint	1	-	62	
		SMD version, device on PCB, 6 cm ² cooling area ³⁾	1	35	-	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =250 μA	600	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}$, $I_{\rm D}=220\mu{\rm A}$	2.5	3	3.5	
Zero gate voltage drain current	I _{DSS}	V _{DS} =600 V, V _{GS} =0 V, T _j =25 °C	1	1	1	μΑ
		V _{DS} =600 V, V _{GS} =0 V, T _j =150 °C	-	10	-	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	$V_{\rm GS}$ =10 V, $I_{\rm D}$ =3.3 A, $T_{\rm j}$ =25 °C	1	0.54	0.6	Ω
		$V_{\rm GS}$ =10 V, $I_{\rm D}$ =3.3 A, $T_{\rm j}$ =150 °C	-	1.5	-	
Gate resistance	R _G	f=1 MHz, open drain	-	1.5	-	Ω



Parameter	Symbol	Conditions	Values		Unit		
			min.	typ.	max.		
Dynamic characteristics							
Input capacitance	C iss	V _{GS} =0 V, V _{DS} =100 V,	-	550	-	pF	
Output capacitance	C oss	f=1 MHz	-	28	-		
Effective output capacitance, energy related ⁵⁾	C o(er)	V _{GS} =0 V, V _{DS} =0 V	-	26	-		
Effective output capacitance, time related ⁶⁾	C _{o(tr)}	to 480 V	-	67	-		
Turn-on delay time	t _{d(on)}		-	17	-	ns	
Rise time	t _r	V _{DD} =400 V, V _{GS} =10 V, I _D =3.3 A,	1	12	1		
Turn-off delay time	$t_{d(off)}$	$R_{\rm G}$ =23.1 Ω	1	75	1		
Fall time	t _f		ı	17	1		
Gate Charge Characteristics							
Gate to source charge	Q _{gs}		1	2	1	nC	
Gate to drain charge	Q _{gd}	V _{DD} =480 V, I _D =3.3 A,	-	10	-		
Gate charge total	Q _g	V _{GS} =0 to 10 V	-	21	27		
Gate plateau voltage	V _{plateau}		1	4.7	1	V	
Reverse Diode							
Diode forward voltage	V _{SD}	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =3.3 A, $T_{\rm j}$ =25 °C	-	0.8	1.2	V	
Reverse recovery time	t _{rr}		-	220	-	ns	
Reverse recovery charge	Q _{rr}	V_R =400 V, I_F = I_S , di_F/dt =100 A/ μ s	-	2.3	-	μC	
Peak reverse recovery current	/ _{rrm}		-	18	-	Α	

¹⁾ J-STD20 and JESD22

²⁾ Pulse width t_p limited by $T_{j,max}$

³⁾ Repetitive avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

 $^{^{4)}~}I_{SD} = I_D,~di/dt \leq 400 A/\mu s,~V_{DClink} = 400 V,~V_{peak} < V_{(BR)DSS},~T_j < T_{jmax},~identical~low~side~and~high~side~switch~the contract of the contract of t$

 $^{^{5)}}$ $C_{\rm o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.

 $^{^{6)}}$ C $_{\rm o(tr)}$ is a fixed capacitance that gives the same charging time as C $_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.



1 Power dissipation

$$P_{\text{tot}}$$
=f(T_{C})

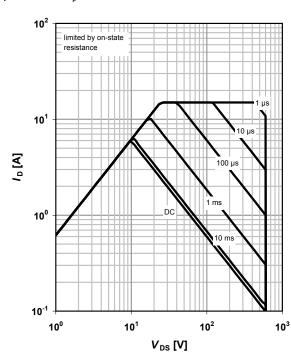
50 40 20 10 0 40 80 120 160

T _c [°C]

2 Safe operating area

$$I_D$$
=f(V_{DS}); T_C =25 °C; D =0

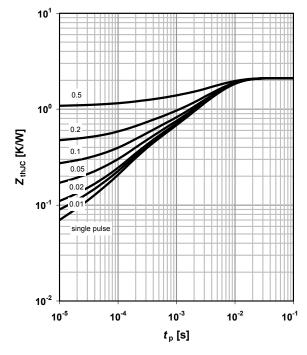
parameter: t_p



3 Max. transient thermal impedance

Z_{thJC} =f(t_P)

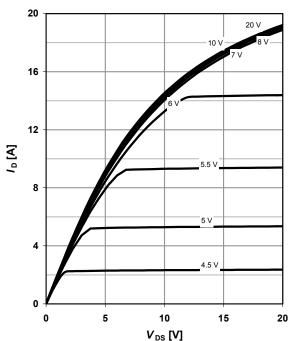
parameter: $D=t_p/T$



4 Typ. output characteristics

$$I_D = f(V_{DS}); T_j = 25 °C$$

parameter: $V_{\rm GS}$

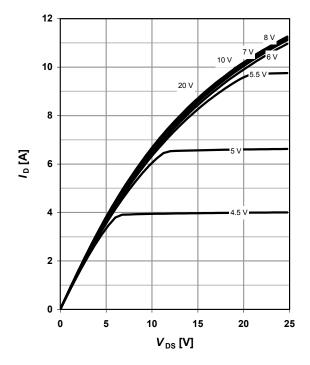




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 150 °C$

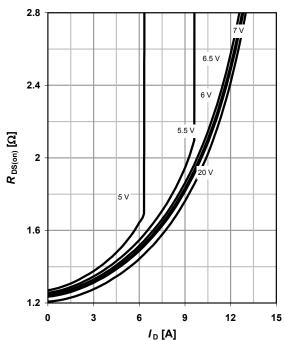
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

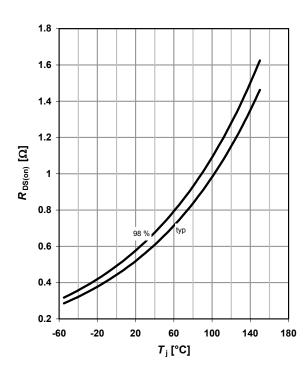
 $R_{DS(on)}$ =f(I_D); T_j =150 °C

parameter: $V_{\rm GS}$



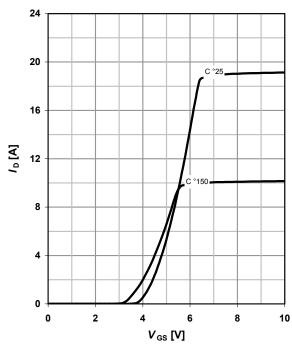
7 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = 3.3 \text{ A}; V_{GS} = 10 \text{ V}$



8 Typ. transfer characteristics

 $I_{\rm D}$ =f($V_{\rm GS}$); $|V_{\rm DS}|$ >2 $|I_{\rm D}|R_{\rm DS(on)max}$ parameter: $T_{\rm j}$

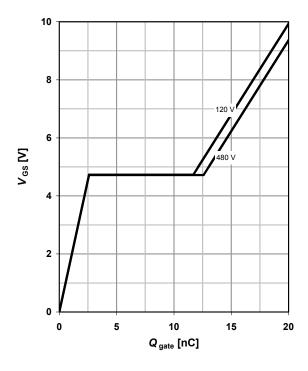




9 Typ. gate charge

 $V_{\rm GS}$ =f(Q $_{\rm gate}$); $I_{\rm D}$ =3.3 A pulsed

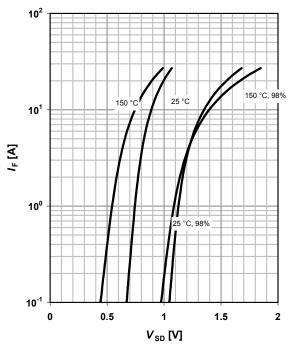
parameter: $V_{\rm DD}$



10 Forward characteristics of reverse diode

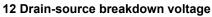
 $I_F = f(V_{SD})$

parameter: T_j

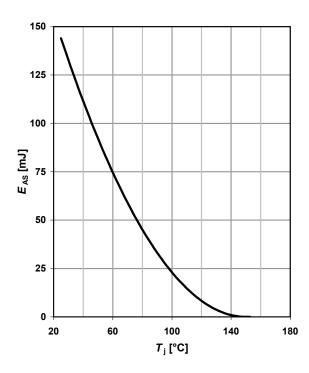


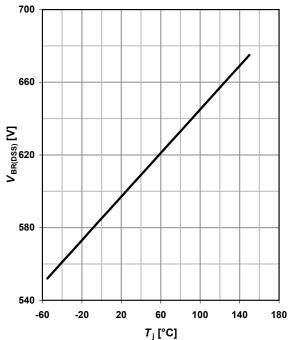
11 Avalanche energy

 E_{AS} =f(T_i); I_D =2.2 A; V_{DD} =50 V



 $V_{BR(DSS)}$ =f(T_j); I_D =0.25 mA





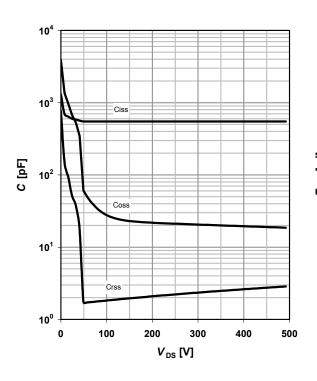


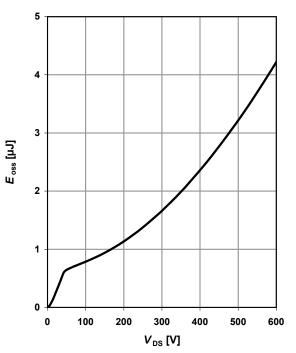
13 Typ. capacitances

$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

14 Typ. Coss stored energy

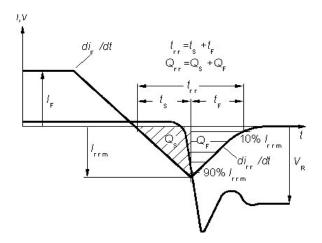
$$E_{oss} = f(V_{DS})$$



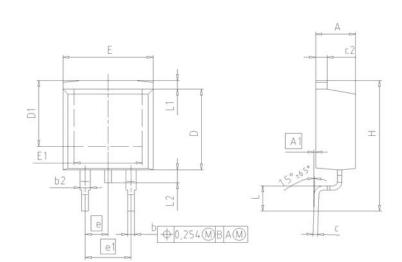


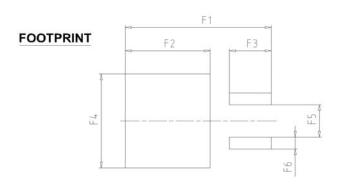


Definition of diode switching characteristics









DIM	MILLIN	IETERS	INCI	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	0.00	0.25	0.000	0.010
b	0.65	0.85	0.026	0.033
b2	0.95	1.15	0.037	0.045
С	0.33	0.65	0.013	0.026
c2	1.17	1.40	0.046	0.055
D	8.51	9.45	0.335	0.372
D1	7.10	7.90	0.280	0.311
E	9.80	10.31	0.386	0.406
E1	6.50	8.60	0.256	0.339
е	2.5	54	0.1	100
e1	5.0	08	0.2	200
N		2		2
н	14.61	15.88	0.575	0.625
L	2.29	3.00	0.090	0.118
L1	0.70	1.60	0.028	0.063
L2	1.00	1.78	0.039	0.070
F1	16.05	16.25	0.632	0.640
F2	9.30	9.50	0.366	0.374
F3	4.50	4.70	0.177	0.185
F4	10.70	10.90	0.421	0.429
F5	3.65	3.85	0.144	0.152
F6	1.25	1.45	0.049	0.057

	ENT NO. 003324
SCALE	0
0	5 5 7.5mm
EUROPEAN	PROJECTION
ISSUE 30-08	

Dimensions in mm/inches



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Infineon Technologies AG
81726 Munich, Germany
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